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INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET N 005917 USA/FET	O.	SERIAL NO. 09/998,372		
				APPLICANT Young Joseph PA	APPLICANT Young Joseph PAIK			
				FILING DATE November 30, 2001		GROUP 3723		
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EXAMINER: Initial If reference considered, whether or not citation is in conformance with MPEP 609; draw like through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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SHEET 2 OF 3 ATTY. DOCKET NO. SERIAL NO. 005917 USA/FET/FET 09/998,372 INFORMATION DISCLOSURE CITATION IN AN **APPLICATION** (PTO-1449) APPLICANT Young Joseph PAIK FILING DATE **GROUP** November 30, 2001 3723 **U.S. PATENT DOCUMENTS EXAMINER'S** FILING INITIALS PATENT NO. DATE NAME **CLASS SUBCLASS** DATE 04/30/02 6,381,564 B1 David et al. 05/03/99 BA 2002/0183986 A1 12/05/02 Stewart et al. 05/30/01 2003/0154062 A1 08/14/03 Daft et al. 10/15/01 6,529,789 B1 03/04/03 Campbell et al. 03/14/02 6,774,998 B1 08/10/04 Wright et al. 12/27/01 6,751,518 B1 06/15/04 Sonderman et al. 04/29/02 6,678,570 B1 01/13/04 Pasadyn et al. 06/26/01 6,735,492 B2 05/11/04 Conrad et al. 07/19/02 **EXAMINER** DATE CONSIDERED

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